

4.4Amps , 600Volts N-Channel MOSFET

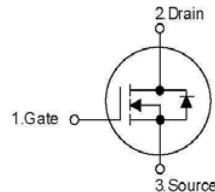
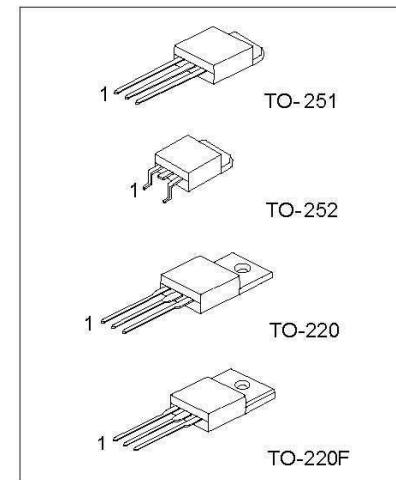
■ Description

The HX4N60(C) N-Channel enhancement mode silicon gate power MOSFET is designed for high voltage, high speed power switching applications such as switching regulators, switching converters, solenoid, motor drivers, relay drivers.

■ Features

- $R_{DS(ON)} = 2.50\Omega @ V_{GS} = 10\text{ V}$
- Low gate charge (typical 16nC)
- High ruggedness
- Fast switching capability
- Avalanche energy specified
- Improved dv/dt capability

■ Symbol



■ Ordering Information

Normal	Lead Free Plating	Package	Pin Assignment			Packing
			1	2	3	
HX4N60(C)-TA3-T	HX4N60(C)L-TA3-T	TO-220	G	D	S	Tube
HX4N60(C)-TF3-T	HX4N60(C)L-TF3-T	TO-220F	G	D	S	Tube
HX4N60(C)-TM3-T	HX4N60(C)L-TM3-T	TO-251	G	D	S	Tube
HX4N60(C)-TN3-T	HX4N60(C)L-TN3-T	TO-252	G	D	S	Tube
HX4N60(C)-TN3-R	HX4N60(C)L-TN3-R	TO-252	G	D	S	Tape Reel

Note: Pin Assignment: G:Gate D:Drain S:Source

 (1) Packing Type (2) Package Type (3) Lead Plating	(1)T:Tube,R:Tape Reel (2)TA3:TO-220,TF3:TO-220F,TM3: TO-251,TN3: TO-252 (3)L:Lead Free Plating Blank: Pb/Sn
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■ Absolute Maximum Ratings ($T_c=25^\circ\text{C}$, unless otherwise specified)

Parameter	Symbol	Ratings				Units
		TO-220	TO-220F	TO-251	TO-252	
Drain-Source Voltage	V_{DSS}			600		V
Gate-Source Voltage	V_{GSS}			± 30		V
Drain Currentet Continuous	I_D	4.4	4.4	2.8		A
		2.8	2.8	1.8		A
Drain Current Pulsed (Note 1)	I_{DP}	17.6	17.6*	11.2		A
Avalanche Energy	Repetitive (Note 1)	E_{AR}	10.6	4.9		mJ
	Single Pulse (Note 2)	E_{AS}	260			mJ
Peak Diode Recovery dv/dt (Note 3)	dv/dt			4.5		V/ns
Total Power Dissipation	$T_c=25^\circ\text{C}$	P_D	100	33	49	W
	Derate above 25°C		0.8	0.26	0.39	W/C
Junction Temperature	T_J			+150		°C
Storage Temperature	T_{STG}			-55~+150		°C

* Drain current limited by maximum junction temperature.



Power Semiconductor Technology

HX4N60 (C)
Power MOSFET

■ Thermal Characteristics

Parameter	Symbol	Ratings				Units
		TO-220	TO-220F	TO-251	TO-252	
Thermal Resistance Junction-Ambient	R_{thJA}	62.5				°C/W
Thermal Resistance, Case-to-Sink Typ.	R_{thCS}	0.5	--	--	--	
Thermal Resistance Junction-Case	R_{thJC}	1.25	3.79	2.56	--	

■ Electrical Characteristics ($T_J=25^\circ\text{C}$, unless Otherwise specified.)

Parameter	Symbol	Test Conditions	Min	Typ	Max	Units
Off Characteristics						
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{GS}=0\text{V}, I_D=250\mu\text{A}$	600	--	--	V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS}=600\text{V}, V_{GS}=0\text{V}$	--	--	1	μA
		$V_{DS}=480\text{V}, T_c=125^\circ\text{C}$	--	--	10	μA
Gate-Body Leakage Current	I_{GSS}	$V_{GS}=30\text{V}, V_{DS}=0\text{V}$	--	--	100	nA
		$V_{GS}=-30\text{V}, V_{DS}=0\text{V}$	--	--	-100	nA
Breakdown Voltage Temperature Coefficient	$\Delta \text{BV}_{DSS}/\Delta T_J$	$I_D=250\mu\text{A}$	--	0.7	--	V/ $^\circ\text{C}$
On Characteristics						
Gate Threshold Voltage	$V_{GS(\text{TH})}$	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	2.0	--	4.0	V
Static Drain-Source On-Resistance	$R_{DS(\text{ON})}$	$V_{DS}=10\text{V}, I_D=2.2\text{A}(\text{TO220, TO220F})$ $I_D=1.4\text{A}(\text{TO251, TO252})$	--	2.0	2.5	Ω
Dynamic Characteristics						
Input Capacitance	C_{iss}	$V_{DS}=25\text{V}, V_{GS}=0\text{V}, f=1\text{MHz}$	--	515	670	pF
Output Capacitance	C_{oss}		--	55	72	pF
Reverse Transfer Capacitance	C_{rss}		--	7.5	8.5	pF
Switching Characteristics						
Turn-On Delay Time	$t_{D(\text{ON})}$	$V_{DD}=300\text{V}, I_D=4.4\text{A}(\text{TO220, TO220F})$ $I_D=2.8\text{A}(\text{TO251, TO252})$ $R_G=25\Omega$ (Note 4, 5)	--	10	--	ns
Rise Time	t_R		--	42	--	ns
Turn-Off Delay Time	$t_{D(\text{OFF})}$		--	38	--	ns
Fall Time	t_F		--	46	--	ns
Total Gate Charge	Q_G	$V_{DS}=480\text{V}, I_D=4.4\text{A}(\text{TO220, TO220F})$ $I_D=2.8\text{A}(\text{TO251, TO252})$ $V_{GS}=10\text{V}$	--	15	--	nC
Gate-Source Charge	Q_{GS}		--	2.5	--	nC
Gate-Drain Charge	Q_{GD}		--	6.6	--	nC
Drain-Source Diode Characteristics						
Drain-Source Diode Forward Voltage	V_{SD}	$V_{GS}=0\text{V}$ $I_{SD}=4.4\text{A}(\text{TO220, TO220F})$ $I_{SD}=2.8\text{A}(\text{TO251, TO252})$	--	--	1.4	V
Continuous Drain-Source Current	I_{SD}	TO220, TO220F	--	--	4.6	A
		TO251, TO252	--	--	2.8	
Pulsed Drain-Source Current	I_{SM}	TO220, TO220F	--	--	18.0	A
		TO251, TO252	--	--	11.2	
Reverse Recovery Time	t_{RR}	$I_{SD}=4.4\text{A}, dI_{SD}/dt=100\text{A}/\mu\text{s}$ (Note 4)	--	300	--	ns
Reverse Recovery Charge	Q_{RR}		--	2.2	--	μC

Notes:

1. Repetitive Rating : Pulse width limited by maximum junction temperature
2. $L=20\text{mH}, I_{AS}=4.4\text{A}, V_{DD}=50\text{V}, R_G=25\Omega$, Starting $TJ=25^\circ\text{C}$
3. $I_{SD}\leq 4.4\text{A}, di/dt\leq 200\text{A}/\mu\text{s}, V_{DD}\leq \text{BV}_{DSS}$, Starting $TJ=25^\circ\text{C}$
4. Pulse Test : Pulse width $\leq 300\mu\text{s}$, Duty cycle $\leq 2\%$
5. Essentially independent of operating temperature

■ Typical Characteristics

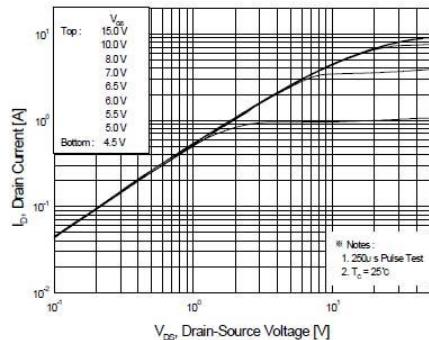


Figure 1. On-Region Characteristics

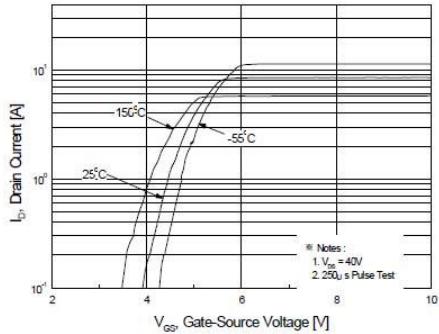


Figure 2. Transfer Characteristics

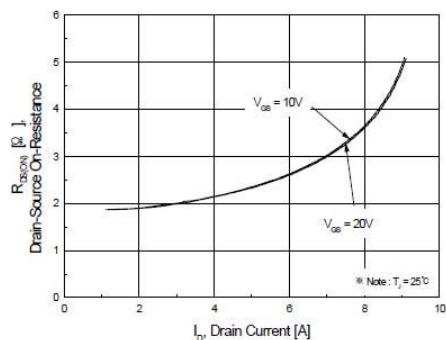


Figure 3. On-Resistance Variation vs
Drain Current and Gate Voltage

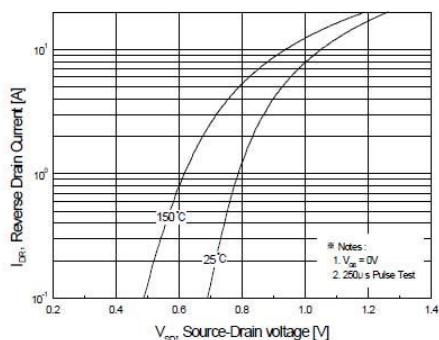


Figure 4. Body Diode Forward Voltage
Variation with Source Current
and Temperature

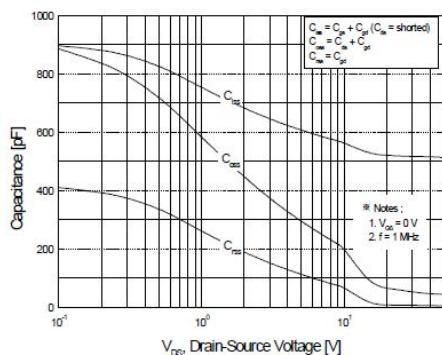


Figure 5. Capacitance Characteristics

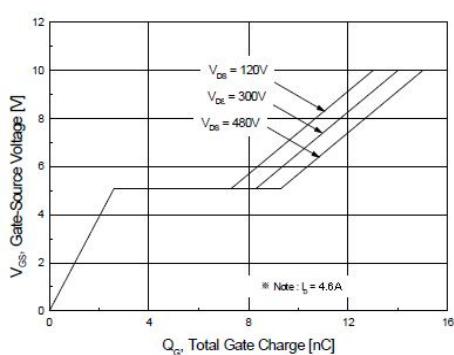
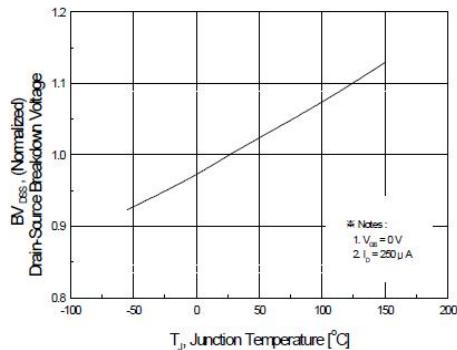
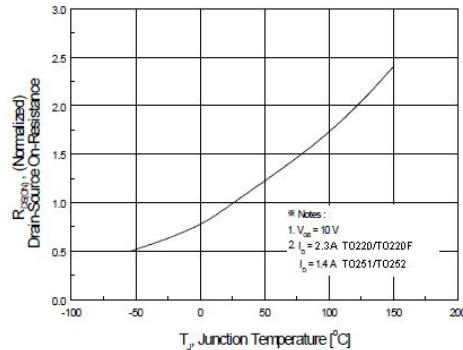


Figure 6. Gate Charge Characteristics

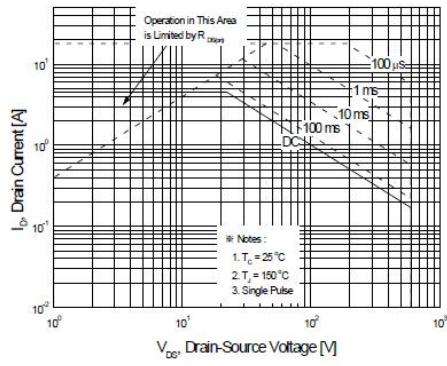
■ Typical Characteristics (Continued)



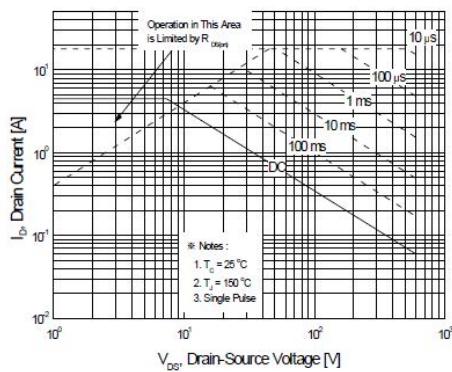
**Figure 7. Breakdown Voltage Variation
vs Temperature**



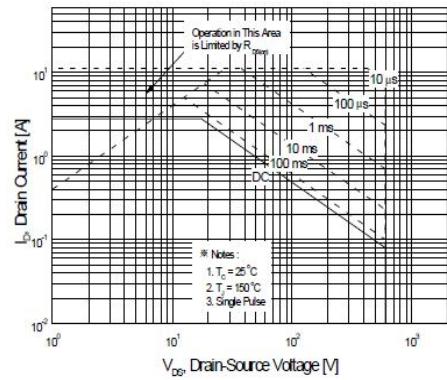
**Figure 8. On-Resistance Variation
vs Temperature**



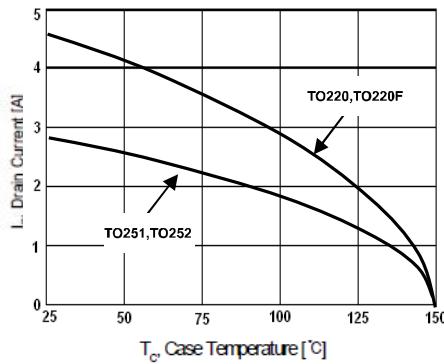
**Figure 9-1. Maximum Safe Operating Area
for TO220**



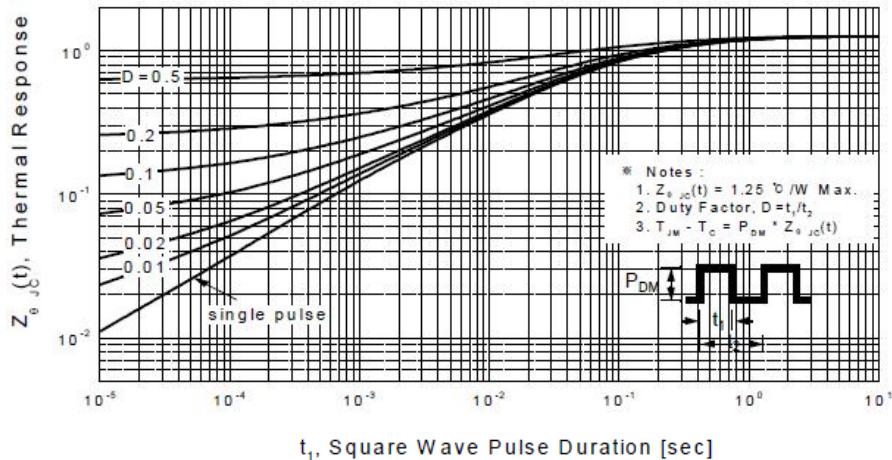
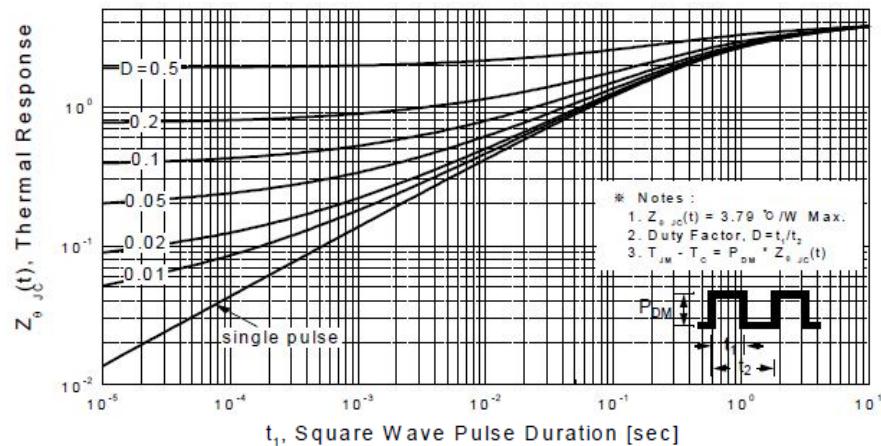
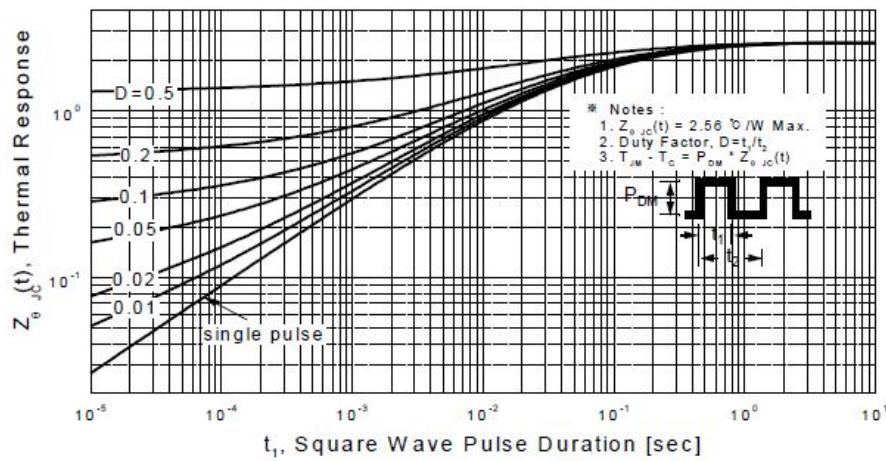
**Figure 9-2. Maximum Safe Operating Area
for TO220F**



**Figure 9-3. Maximum Safe Operating Area
for TO251, TO252**



**Figure 10. Maximum Drain Current
vs Case Temperature**

■ Typical Characteristics (Continued)

Figure 11-1. Transient Thermal Response Curve TO220

Figure 11-2. Transient Thermal Response Curve for TO220F

Figure 11-3. Transient Thermal Response Curve for TO251/ TO252